

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination HECTOR ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0171797	11-2002	Ichioka et al.	349/149
*	B	US-2003/0063248	04-2003	Komeno et al.	349/149
*	C	US-5,625,476	04-1997	Kim, Dong-kyu	349/149
*	D	US-5,182,620	01-1993	Shimada et al.	257/72
*	E	US-5,159,477	10-1992	Shimada et al.	349/39
*	F	US-5,130,829	07-1992	Shannon, John M.	349/111
*	G	US-2002/0008794	01-2002	Song et al.	349/40
*	H	US-6,268,898	07-2001	Ihara, Hirofumi	349/155
*	I	US-6,462,722	10-2002	Kimura et al.	345/76
*	J	US-5,734,450	03-1998	Irie et al.	349/39
*	K	US-6,567,064	05-2003	Song et al.	345/94
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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